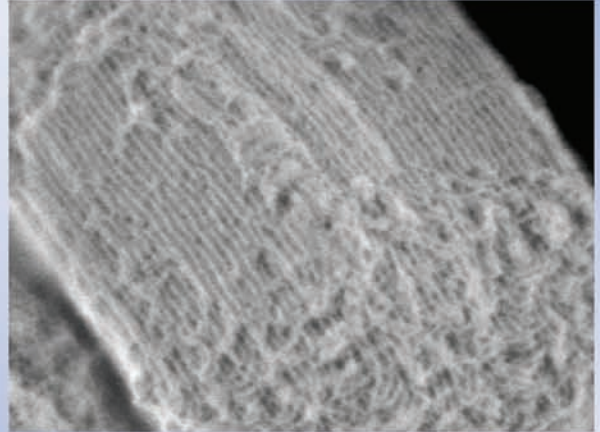


# JSM-7800F

Thermal Field Emission Scanning Electron Microscope



## Extreme resolution



Incident electron energy: 0.1 kV (GB)

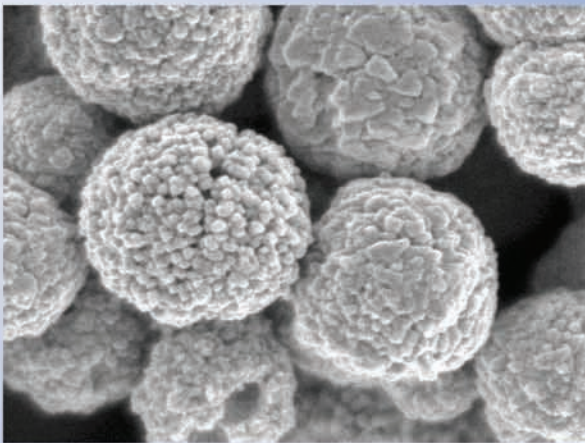
100nm

### Meso-porous silica

Very fine porous structures are observed without conductive coating.

*We provide extreme performance. You enjoy freedom.*

## No limitation in specimens



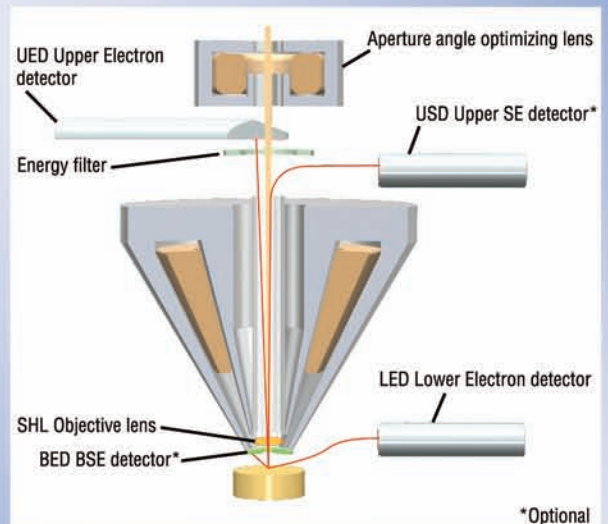
### Fe<sub>3</sub>O<sub>4</sub> Nano Cluster

100nm

Fe<sub>3</sub>O<sub>4</sub> nano-particle cluster  
The super hybrid lens allows you to study magnetic materials at high magnifications.

The SEM image courtesy of

Dr. Takanari Togashi, Prof. Tadafumi Adschiri, Advanced Institute for Material Research, Tohoku University



The newly developed super hybrid objective lens (SHL) provides the resolution of 0.8nm at 15kV and 1.2nm at 1kV. The SHL objective lens allows researchers to study various samples at high magnification.

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